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PATENT NUMBER and ISSUE DATE

U.S. **UTILITY** Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10056906	01/24/2002	414	866	3652	GARREN

APPLICANTS: Renken Wayne;

X 73/866

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH		RESCIND	

		ATTORNEY DOCKET NO
Foreign priority claimed	☐ yes ☐ no	
35 USC 119 conditions met	☐ yes ☐ no	M-12467
Verified and Acknowledged Examiners's intials		

TITLE : Process condition sensing wafer and data analysis system

U.S.DEPT. OF COMM./PAT.& TM-PTO-436L(Rev. 12-34)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
	Assistant Examiner	Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
	Primary Examiner		
☐ TERMINAL DISCLAMER	PREPARED FOR ISSUE	Application Examiner	

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